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31 An approach for online repair and yield enhancement of VLSI/WSI redundant memories

Shen, Y.-N.; Lombardi, F.;

CompEuro '91. 'Advanced Computer Technology, Reliable Systems and Applications'. 5th Annual European Computer Conference. Proceedings., 13-1 May 1991

Pages:685 - 689

[Abstract] [PDF Full-Text (404 KB)] IEEE CNF

32 Wafer scale integration (WSI) of programmable gate arrays (PGA's McDonald, J.F.; Dabral, S.; Philhower, R.; Russinovich, M.E.;

Wafer Scale Integration, 1990. Proceedings., [2nd] International Conference on , 23-25 Jan. 1990

Pages: 329 - 338

[Abstract] [PDF Full-Text (588 KB)] IEEE CNF

33 A 50 ns 16 Mb DRAM with a 10 ns data rate

Kalter, H.; Barth, J.; Dilorenzo, J.; Drake, C.; Fifield, J.; Hovis, W.; Kelley, G., Lewis, S.; Nickel, J.; Stapper, C.; Yankosky, J.;

Solid-State Circuits Conference, 1990. Digest of Technical Papers. 37th ISSCC 1990 IEEE International , 14-16 Feb. 1990

Pages: 232 - 233, 303

[Abstract] [PDF Full-Text (720 KB)]

34 Approaches for the repair of VLSI/WSI RRAMs by row/column dele Lombardi, F.; Huang, W.K.;

Fault-Tolerant Computing, 1988. FTCS-18, Digest of Papers., Eighteenth

International Symposium on , 27-30 June 1988 Pages: 342 - 347

[Abstract] [PDF Full-Text (444 KB)] IEEE CNF

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McPartland, R.J.; Loeper, D.J.; Higgins, F.P.; Singh, R.; MacDonald, G.; Komo G.; Aymeloglu, S.; DePaolis, M.V.; Leung, C.W.;

Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000 , 21-24 May 2000

Pages: 287 - 289

[PDF Full-Text (240 KB)] IEEE CNF [Abstract]

2 A 3.3-V 12 ns 16 Mb CMOS SRAM

Goto, H.; Ohkubo, H.; Kondou, K.; Ohkawa, M.; Mitani, H.; Horiba, S.-I.; Soe M.; Hayashi, F.; Hachiya, Y.; Shimizu, T.; Ando, M.; Matsuda, Z.; Solid-State Circuits Conference, 1992. Digest of Technical Papers. 39th ISSCC 1992 IEEE International , 19-21 Feb. 1992 Pages: 216 - 217, 288

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3 Built in self repair for embedded high density SRAM

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